

# **Analog and Digital Systems (UEE505)**

## **Lecture # 5**

### **FET ( Field Effect Transistor)**



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# FET Introduction

- Unipolar Device
- Voltage controlled Device

Few important advantages of FET over conventional Transistors:

- Very high input impedance ( $\approx 10^9$ - $10^{12} \Omega$ )
- Source and drain are interchangeable in most Low-frequency applications
- Low Voltage Low Current Operation is possible (Low-power consumption)
- Less Noisy
- Very small in size, occupies very small space in ICs

# Types of FET

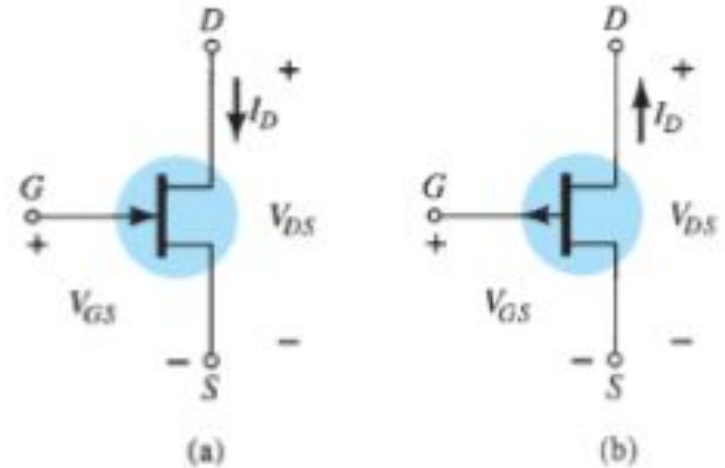
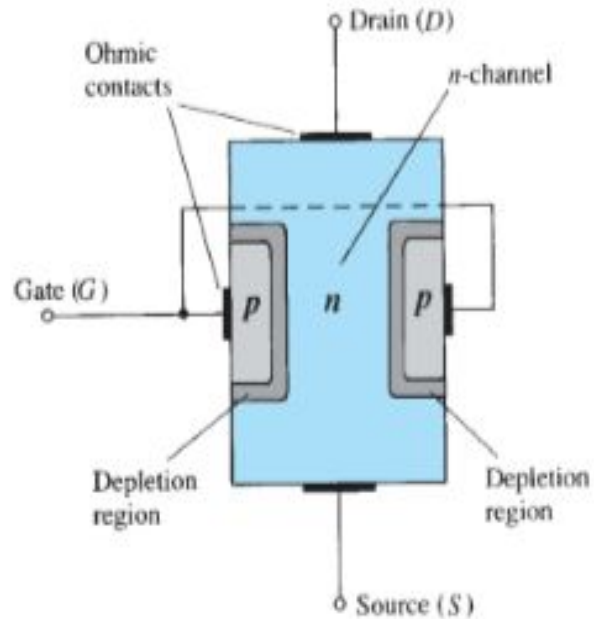
❖ JFET: Junction FET

❖ MOSFET: Metal–Oxide–Semiconductor FET

- *D-MOSFET: Depletion MOSFET*

- *E-MOSFET: Enhancement MOSFET*

# JFET Construction



(a) n-channel & (b) p-channel

# JFET Operation

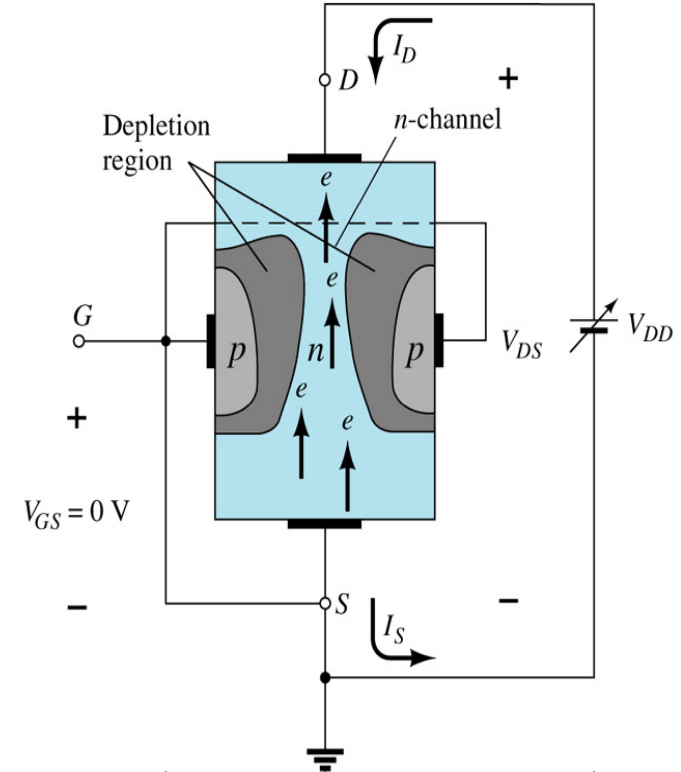
There are three basic operating conditions for a JFET:

- $V_{GS} = 0V$ ,  $V_{DS}$  increasing to some positive value
- $V_{GS} < 0V$ ,  $V_{DS}$  at some positive value
- Voltage-controlled resistor

# $V_{GS} = 0V$ , $V_{DS}$ at some positive value

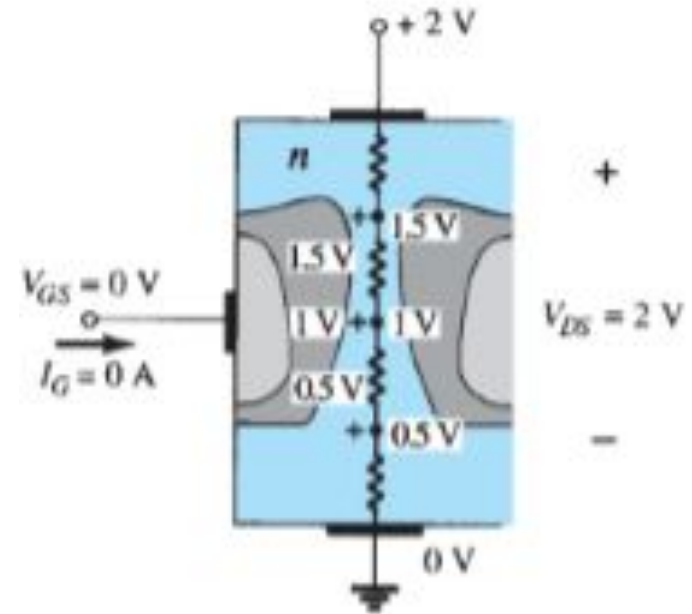
Three things happen:

- ❑ the depletion region between p-gate and n-channel increases as electrons from n-channel combine with holes from p-gate.
- ❑ increasing the depletion region, decreases the size of the n-channel which increases the resistance of the n-channel.
- ❑ But even though the n-channel resistance is increasing, the current ( $I_D$ ) from Source to Drain through the n-channel is increasing. This is because  $V_{DS}$  is increasing.



$V_{GS} = 0V$ ,  $V_{DS}$  at some positive value

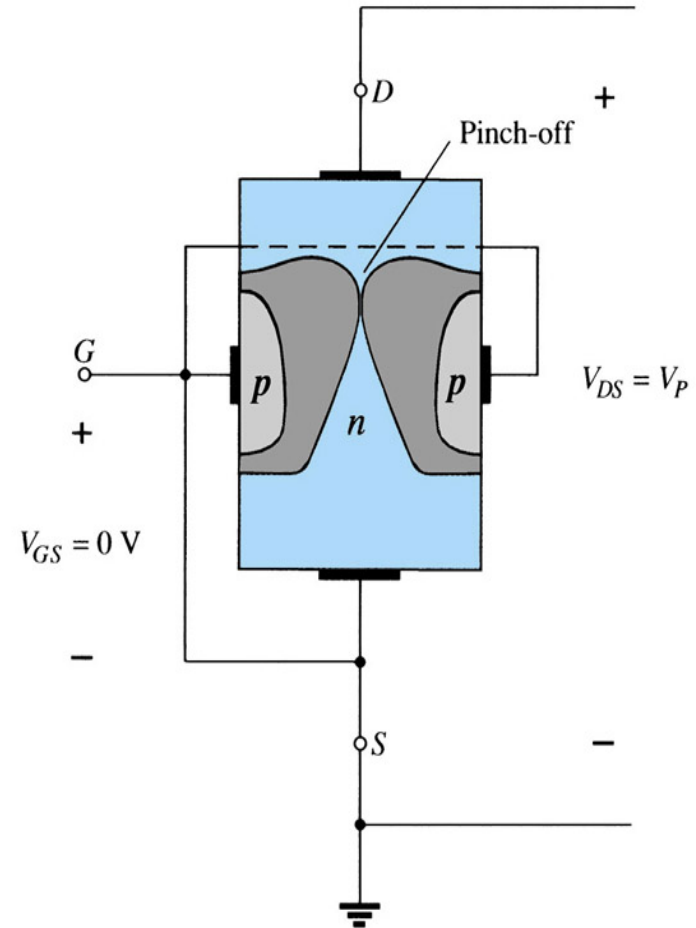
- Drain current will establish the voltage level through the channel.
- The result: upper region of the p-type material will be reversed biased by about 1.5V as compared to lower region which is reversed biased by 0.5V.



# JFET Operation : Pinch off

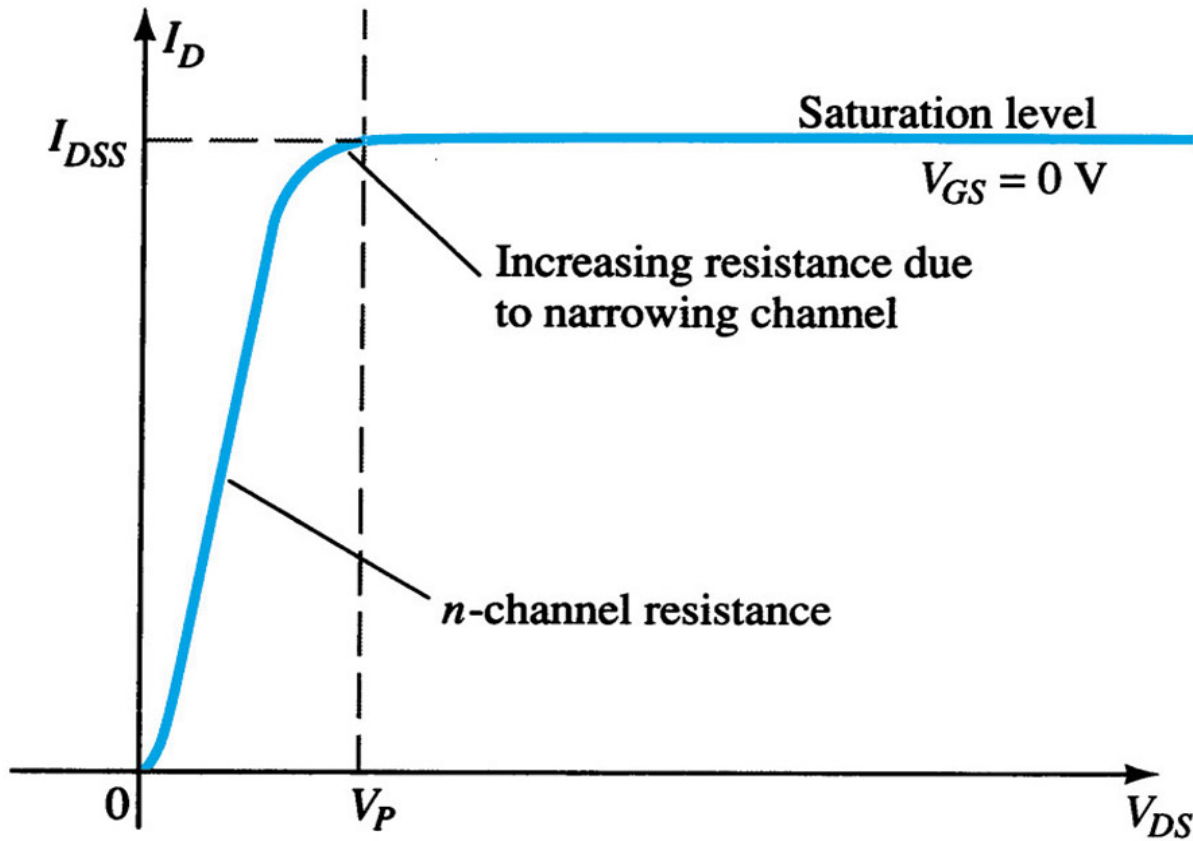
- $V_p$  = pinch off voltage.
- Drain Current maintain the saturation level defined as  $I_{DSS}$ .
- Once the  $V_{DS} > V_p$ , the JFET has the characteristics of a current source.
- $I_{DSS}$  is the max drain current for a JFET with short circuit connection from gate to source and is defined by the conditions :

$$V_{GS} = 0V \text{ \& } V_{DS} > |V_p| .$$



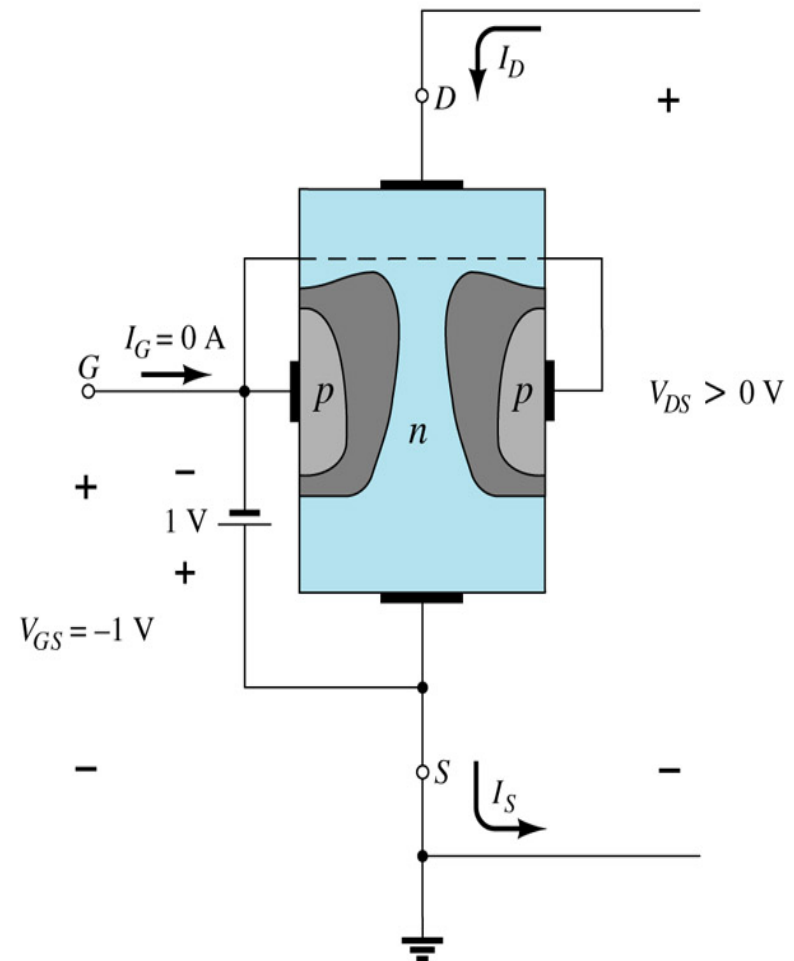


# Drain Characteristics at $V_{GS} = 0V$

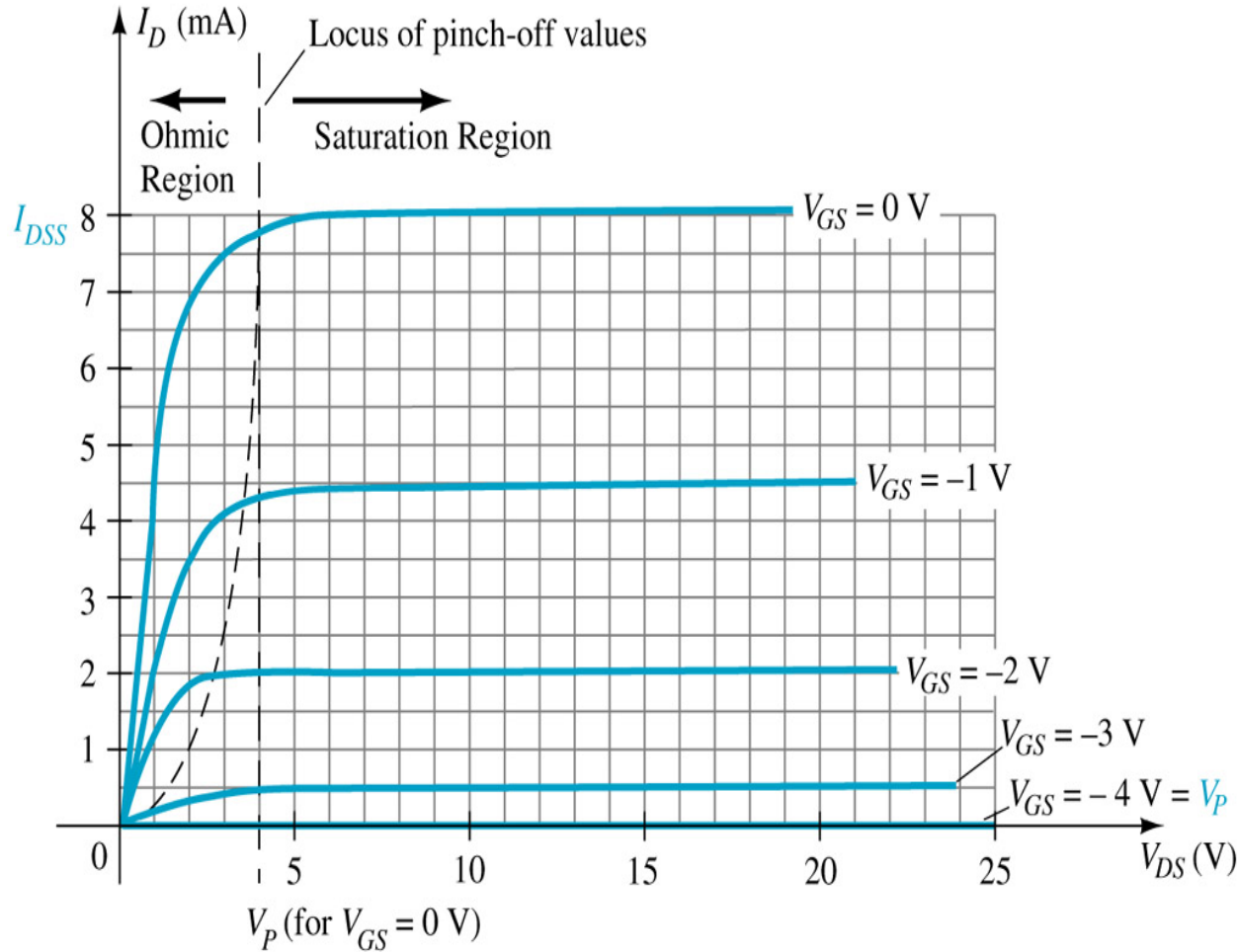


# $V_{GS} < 0V$ , $V_{DS}$ at some positive value

- For n-channel devices, the controlling voltage  $V_{GS}$  is made more and more negative from its  $V_{GS} = 0V$  level.
- The effect of the applied negative  $V_{GS}$  is to establish depletion regions similar to those obtained with  $V_{GS} = 0V$  but at lower level of  $V_{DS}$  saturation level reached.



# Drain Characteristics at $V_{GS} < 0V$

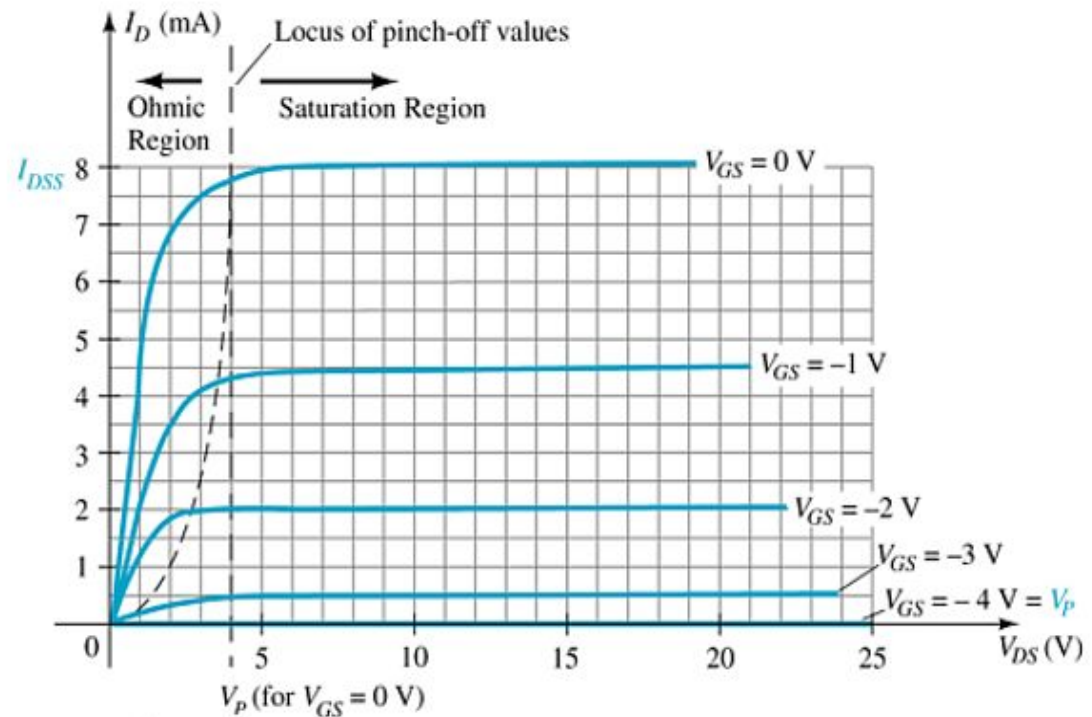


Note: At high levels of  $V_{DS}$ , the JFET reaches a breakdown situation.  $I_D$  increases uncontrollably if  $V_{DS} > V_{DS \text{ max}}$ .

# Voltage Variable Resistor

The region to the left of the pinch-off point is called the ohmic region. It can be used as a variable resistor.

The JFET can be used as a variable resistor, where  $V_{GS}$  controls the drain-source resistance ( $r_d$ ). As  $V_{GS}$  becomes more negative, the resistance  $r_d$  increases



$$r_d = \frac{r_o}{(1 - V_{GS}/V_P)^2}$$

# JFET Equations

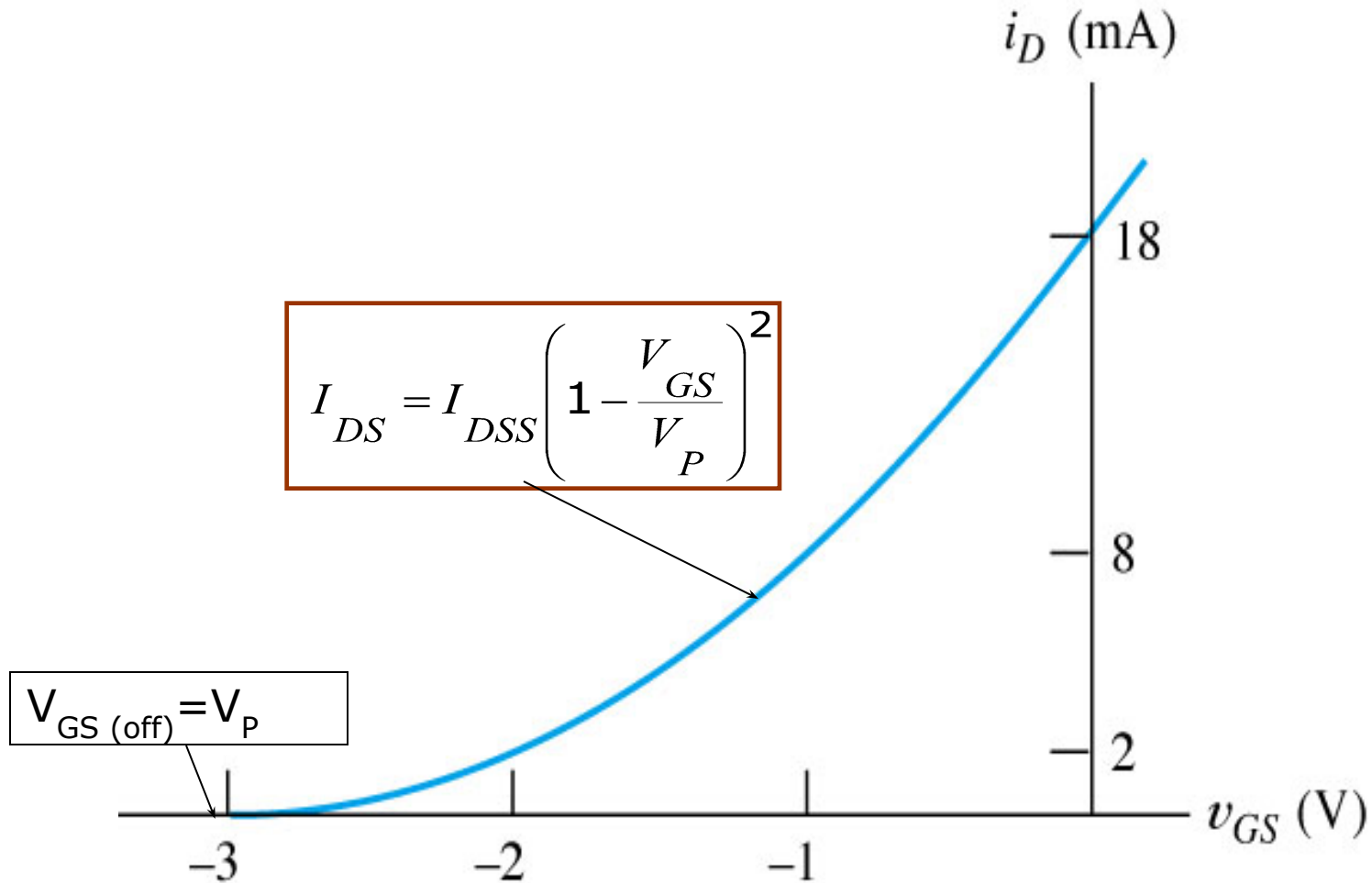
- **Non-saturation (Ohmic) Region:**

$$I_{DS} = \frac{2I_{DSS}}{V_P^2} \left[ (V_{GS} - V_P)V_{DS} - \frac{V_{DS}^2}{2} \right]$$

- **Saturation (or Pinch off) Region:**

$$I_{DS} = I_{DSS} \left( 1 - \frac{V_{GS}}{V_P} \right)^2$$

# Transfer (Mutual) Characteristics



# Applications of JFET

- ☐ Low noise amplifier
- ☐ Used as voltage variable resistor in op amps.
- ☐ Analog switch
- ☐ Multiplexer
- ☐ Digital Switching Circuits

# References

❖ For more details, refer to:

- *Boylestad R. L., Electronic Devices and Circuit Theory, Pearson Education*
- *Neamen, Donald A., Electronic Circuit Analysis and Design, McGraw Hill*
- *Sedra A. S. and Smith K. C., Microelectronic Circuits, Oxford University Press*